Figure 1: SIMS:ZERO system equipped with a cesium low temperature ion source. This system is installed at zeroK NanoTech.

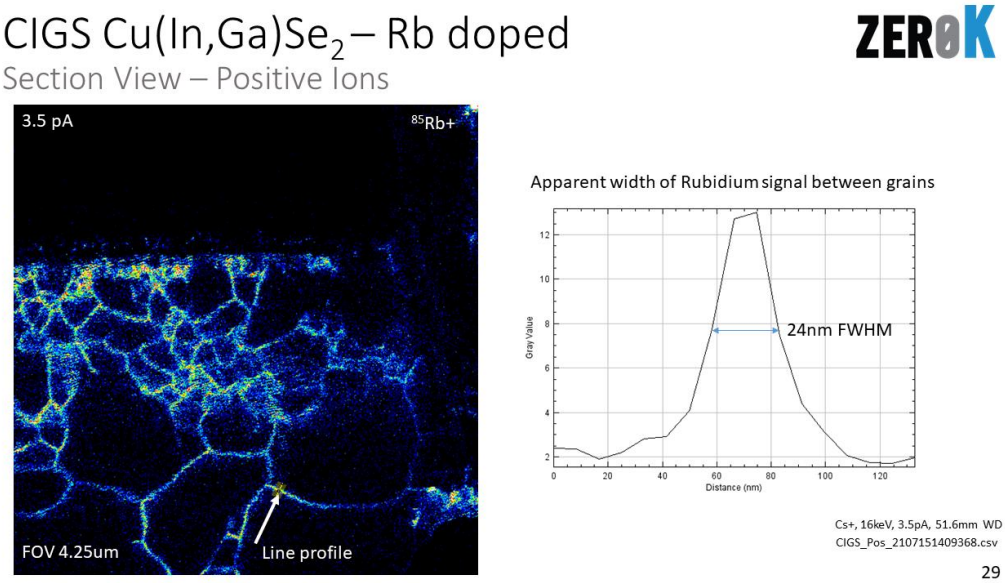

Figure 2: High-resolution elemental mapping of rubidium In a CIGS solar-cell with SIMS:ZERO. A CIGS solar cell material was sectioned at 45 degrees, then the locations of rubidium where mapped by sputtering at normal incidence and collecting the secondary ions with our double-focusing magnetic sector mass-spectrometer. Rubidium was found to agglomerate at the grain boundaries and can be located with few-nm precision.